



Advances in Radiation Detection and Monitoring

Guest Editor:

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Message from the Guest Editor

Dear Colleagues,

With regard to the rapid development of the nuclear industry, medical/biological sciences and space exploration, many new methods, new instruments and new applications for radiation detection and monitoring in those fields have shown a strong development for several years. Despite scientific and technological progress, there are several challenges and future developments that characterize the present academic, space and industry studies with respect to detection instrument design, new phenomenon finding and the application of new methods.

Considering the interest in this theme, we are organizing a Special Issue titled "Advances in Radiation Detection and Monitoring", aimed at reporting the most recent findings from researchers and professionals in the sector, within the scope of the following themes:

- New methods in radiation detection and monitoring;
- New materials for radiation detection and monitoring;
- New instruments in radiation detection and monitoring;
- New applications in radiation detection and monitoring.



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Prof. Dr. Zhongchen Wu
Guest Editor

Special Issue



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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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